

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application: H. MATSUOKA et al
Serial No. 09/592,648
Filed: June 13, 2000

Group Art: 2814
Examiner: D. Nguyen
For: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE
AND A METHOD OF MANUFACTURE THEREOF

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450


July 31, 2003

Sir:

In accordance with the duty of disclosure, the Applicants inform the Examiner of the documents cited during prosecution of the parent application, USSN 09/592,648.

The Applicants request the Examiner to initial and return a copy of the attached PTO-1449 form as an indication that the references have been considered.

Respectfully submitted,



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Date: July 31, 2003

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIT-202-02	SERIAL NO.
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT H. MATSUOKA et al	
		FILING DATE 07/31/03	GROUP 2814

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA	6,130,449	10/2000	Matsuoka et al			
	AB	6,100,117	08/2000	Hao et al			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATIO	
							YES	NO
	AL	07-066299	03/10/95	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM						<input type="checkbox"/>	<input type="checkbox"/>
	AN						<input type="checkbox"/>	<input type="checkbox"/>
	AO						<input type="checkbox"/>	<input type="checkbox"/>
	AP						<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	Ahn et al "Bidirectional Matched Global Bit Line Scheme for High Density DRAMs", Symposium on VLSI Circuits, 1993, pp. 91-92.
	AS	
	AT	

EXAMINER	DATE CONSIDERED
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form next communication to applicant.